12. (New) The composite substrate of claim 1, wherein the electrode is a metallic electrode comprising palladium, rhodium, iridium, rhenium, ruthenium, platinum, silver, gold, tantalum, nickel, chromium or titanium.

- 13. (New) The composite substrate of claim 1, wherein the electrode is a metallic electrode compaising Pd, Pt, Au, Ag or an alloy thereof.
- 14. (New) The EL device of claim 7, wherein the second electrode is a transparent electrode of ITO or IZO.
- 15. (New) The EL device of claim 14, wherein said ITO comprises a proportion of SnO<sub>2</sub> to In<sub>2</sub>O<sub>3</sub> of from 1 to 20% by weight.
- 16. (New) The ED device of claim 14, wherein said IZO comprises a proportion of ZnO to In<sub>2</sub>O<sub>3</sub> of about 12 to 32% by weight.
  - 17. (New) The EL device of claim 14, wherein the second electrode is silicon-based.
- 18. (New) The EL device of claim 17, wherein the silicon-based electrode comprises polycrystalline silicon (p-Si), amorphous silicon (a-Si) or single crystal silicon.
- 19. (New) The EL device of claim 17, wherein said silicon-based electrode comprises a dopant to impart conductivity.
- 20. (New) The EL device of claim 9, wherein said dopant comprises B, P, As, Sb or Al in an amount of about 0.001 to 5 at.%.
- 21. (New) The EL device of claim 14, wherein said second electrode has a resistivity of up to 1  $\Omega$ ·cm.
- 22. (New) The EL device of claim 21, wherein said second electrode has a resistivity of from about 0.003 to 0.1  $\Omega$ ·cm.